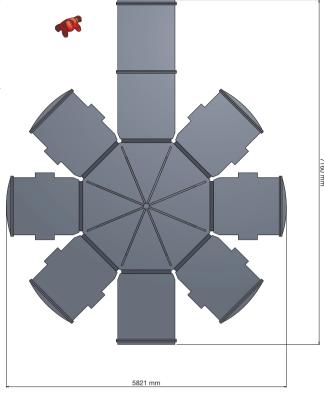
Overall system dimensions

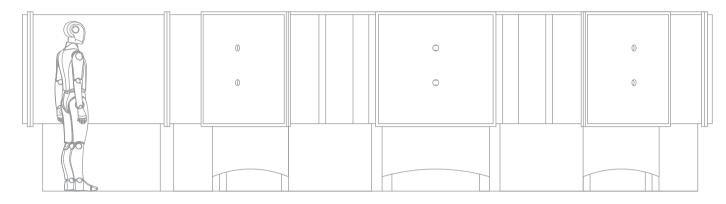


Ancillary systems, i.e. pumps, control units or automated loading stations are not shown.



Note: Dimensions and system configuration may be subject to change without prior notice.





Octopus III

PECVD Cluster Deposition System for Heterojunction Cell Devices

System key data

Throughput, nominal	2'400 wafers/hr (and scalable)
Footprint L x W x H	7'160 x 5'821 x 1'860 mm
No. cells per carrier plate	24
PECVD deposition mode	RF - 13.56 MHz, capacity coupled
Process temperature	> 200°C (permanent mode)
System base pressure	< 5x10 ⁻⁶ bar
Chamber cleaning	In-situ (NF3)
Wafer size	6" (M0 M2 M4)
Film thickness	10 20 nm (per substrate side)
Thickness uniformity	< 5 % (across entire carrier plate)
Thin film type	a-Si:H (intrinsic and doped)
Minority carrier lifetime	> 7 ms (intrinsic), > 5 ms (intrinsic + doped)

Contact Offices

Headquarters

Indeotec SA Rue du Puits-Godet 12A 2000 Neuchâtel Switzerland

+41 32 545 3024 sales@indeotec.com

China

DKSH China Co., Ltd. Unit 605-507, Bldg. 2, Xinglian Bldg. No. 1535, Shanghai 200233, PRC

+86 (21) 5383 8811 Ext 160 christy.liu@dksh.com

Taiwan

DKSH Taiwan Ltd 10th floor, No. 22, Lane 407, Sec. 2 Tiding Blvd., Taipei 114-93 Taiwan

+886 (2) 8752 6666 Ext 674 nick.chen@dksh.com

REACTOR MIRROR TOP
REACTOR MIRROR BOTTOM

© INDFOtec SA - MARCH 2017

PRODUCT INFORMATION





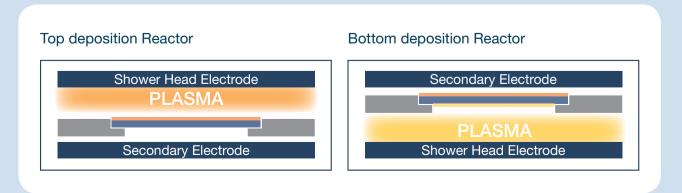


Octopus III is a fully automated thin film deposition system for the mass production of high-efficiency cell devices (HJT cells). The cluster platform configuration and the proprietary PECVD process chambers have been optimized for excellent passivation layer quality, low footprint and significantly reduced handling steps.

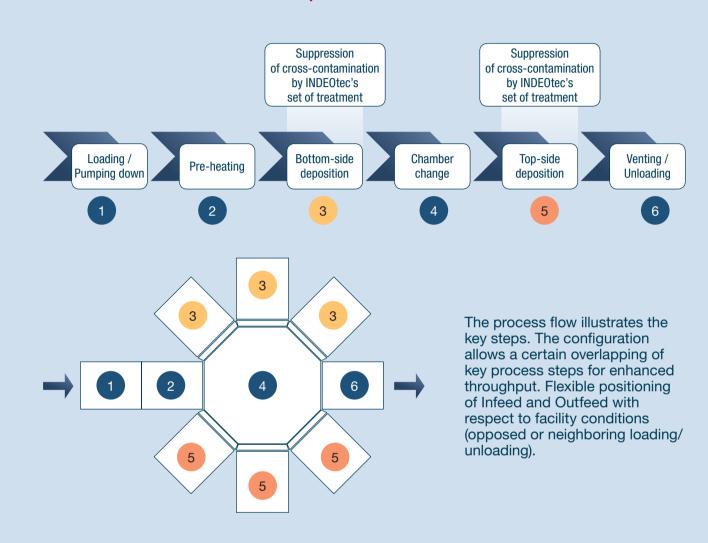
System features

- > Cluster system platform, proprietary RF-VHF deposition design
- > Top and bottom side deposition by proprietary Mirror Reactor concept
- > No wafer flipping necessary between top & bottom deposition
- > Intrinsic and doped layers deposition into the same reactor thanks to **Anti Cross-Contamination Treatment**
- > Pre-heating chamber for simultaneous wafer and carrier heating
- Fully automated carrier loading
- Throughput can be upscaled
- Mirror Reactor concept compatible with thin wafer

Mirror Reactor concept



Process flow with mirror concept and Anti Cross-Contamination Treatment



Deposition stack

Standard/Bifacial-HJT **IBC-HJT** Mask and carrier in one single piece, with deposition from bottom a-Si:H (i) a-Si:H (i) Textured wafer Textured wafer a-Si:H (i) a-Si:H (i) a-Si:H (n) a-Si:H (p) a-Si:H (n)